

Notice of References Cited	Application/Control No. 10/525,383	Applicant(s)/Patent Under Reexamination MINODA ET AL.	
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U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 08-034860	02-1996	JP	Miyamoto et al	
	O	JP 2002-225075	08-2002	JP	Akimoto	
	P	JP 06-107750	04-1994	JP	Meikei et al	
	Q					
	R					
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